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THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Zhidan TOLT

Docket No.:

372668-00101

Serial No.

10/807,890

Art Unit:

2879

Filed:

March 24, 2004

Examiner:

Not yet assigned

Title:

ELECTRON EMITTING COMPOSITE BASED ON REGULATED NANO-STRUCTURES AND

A COLD ELECTRON SOURCE USING THE COMPOSITE

Mail Stop OIPE Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

TRANSMITTAL FOR INFORMATION DISCLOSURE STATEMENT

Enclosed for filing in the above-identified application is:

☑ Information Disclosure Statement;

☑ Form PTO-1449; and

A postcard as return receipt of the above-listed items.

The Commissioner is authorized to charge any required fees, or credit any overpayment to Deposit Account Number 50-2778.

Respectfully submitted,

Dated: August 12, 2004

Anthony B. Diepenbrock III/

Reg. No. 39,960

DECHERT LLP Customer No. 37509

CERTIFICATE OF MAILING (37 CFR 1.8(a))

I hereby certify that this paper (along with any referred to as being attached or enclosed) is being attoosied on August 12, 2004, with the U.S. Postal Service as first class mail in an envelope addressed to: Mail Stop OIPE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA, 22313-1450.

Date: August 12, 2004

Yolette Yturfalde-Owen

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INFORMATION DISCLOSURE STATEMENT

Applicant submits herewith the references listed on the attached form PTO-1449 of which Applicant is aware and in respect of which there may be a duty to disclose in accordance with 37 CFR 1.56.

The filing of this information disclosure statement shall not be construed as a representation that a search has been made (37 CFR 1.97(g)), nor as an admission that the information cited is, or is considered to be, material to patentability, nor an admission that no other material information exists.

The filing of this information disclosure statement shall not be construed as an admission against interest in any manner.

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Date: August 12, 2004

Yolette Yturralde Owen

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	CITE No.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	AA	5,564,959	10/1996	SPINDT et al.	445	24
	AB	5,869,922	02/1999	Tolt	313	310
	AC	6,440,761	08/2002	Сног	438	20
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	AE	6,448,701	09/2002	Hsu	313	309
	AF	6,515,415	02/2003	Morita	313	496

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	CITE No.	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASSIFICATION
	AG					

NON-PATENT DOCUMENTS

EXAMINER INITIALS	CITE No.	INCLUDE AS APPLICABLE: AUTHOR, TITLE DATE, PUBLISHER, EDITION OR VOLUME, PERTINENT PAGES)	
	AH	Bonard, J.M. et al., Appl. Phys. Lett. 73, 918 (1998).	
	AI	Chhowalla, J. et al., Appl. Phys., 90, 5308 (2001).	
	AJ	Dean, K.A. et al., Appl. Phys. Lett. 75, 3017 (1999).	
	AK	Fowler, R.H. et al., Proc. R. Soc. London, A19, 173 (1928).	
	AL	Geis, M.W. et al., Lincoln Lab. J. 10, 3 (1997).	
	AM	Gullorn, M.A. et al., Appl. Phys. Lett. 79, No. 21, 3506 (2001).	
	AN	Li, J. et al., Appl. Phys. Lett., 75, 367 (1999).	
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AQ	Read, M.E. et al., Proceedings of the 2001 Particle Accelerator Conference, Chicago.
AR	Ren, F. et al., Science 282, 1105 (1998).
 AS	Rinzler, G. et al., Science, 269, 1550 (1995).
AT	Saito, Y. et al., Jpn. J. Appl. Phys., Part 2 36, L 1340 (1997).
AU	Wang, Q.H. et al., Appl. Phys. Lett. 78, 1294 (2001).

EXAMINER	DATE CONSIDERED			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance				
and not considered. Include copy of this form with next communication to applicant				

Information Disclosure Statement (Form PTO 1449) 2 of 2 C:\SFNET\MS\Word\999999.01 8/12/04 5:34 PM